

Search Notes

Application/Control No.

10/618,402

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

TEE ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
updated	updated	2/24/2005	<i>ms</i> SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR